Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/811,440	AKAHANE ET AL.	
Examiner	Art Unit	

2664

CHUONG T. HO

	SEARCHED				
	Class	Subclass	Date	Examiner	
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	370	357			
	370	355			
	709	238			
	709	239			
	370	390			
	370	469			
	370	409			
	370	410			
	709	245		V	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	401	10/31/05	CH
370	410		
370	409		
370	392		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/811,440	AKAHANE ET AL.	
Examiner	Art Unit	
CHUONG T. HO	2664	

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	. Class	Subclass	Date	Examiner
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	709	242		
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	709	203	<b>1</b>	

INTERFERENCE SEARCHED			
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370	395.52		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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WEST (Test rearch,	10/21/05	CH	
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EAST		}	
STM			
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Consulting with	14/3/05	CH	
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